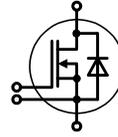


# HiPerFET™ Power MOSFETs

## in ECO-PAC 2

(Electrically Isolated Back Surface)

Single MOSFET



Pin arrangement see outlines

MOSFET			
Symbol	Conditions	Maximum Ratings	
$V_{DSS}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$	100	V
$V_{DGR}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$ ; $R_{GS} = 1\text{ M}\Omega$	100	V
$V_{GS}$	Continuous	$\pm 20$	V
$V_{GSM}$	Transient	$\pm 30$	V
$I_{D25}$	$T_C = 25^\circ\text{C}$ (MOSFET chip capability)	165	A
$I_{D(RMS)}$	External lead (current limit)	76	A
$I_{DM}$	$T_C = 25^\circ\text{C}$ <sup>1)</sup>	720	A
$I_{AR}$	$T_C = 25^\circ\text{C}$	180	A
$E_{AR}$	$T_C = 25^\circ\text{C}$	60	mJ
$E_{AS}$	$T_C = 25^\circ\text{C}$	3	J
$dv/dt$	$I_S \leq I_{DM}$ , $di/dt \leq 100\text{ A}/\mu\text{s}$ , $V_{DD} \leq V_{DSS}$ $T_J \leq 150^\circ\text{C}$ , $R_G = 2\ \Omega$	5	V/ns
$P_D$	$T_C = 25^\circ\text{C}$	400	W

Symbol	Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		min.	typ.	max.
$V_{DSS}$	$V_{GS} = 0\text{ V}$ , $I_D = 3\text{ mA}$	100		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 8\text{ mA}$	2.0		4.0 V
$I_{GSS}$	$V_{GS} = \pm 20\text{ V}$ , $V_{DS} = 0$			$\pm 100\text{ nA}$
$I_{DSS}$	$V_{DS} = V_{DSS}$ ; $T_J = 25^\circ\text{C}$ $V_{GS} = 0\text{ V}$ ; $T_J = 125^\circ\text{C}$			100 $\mu\text{A}$ 2 mA
$R_{DS(on)}$	$V_{GS} = 10\text{ V}$ , $I_D = 90\text{ A}$ <sup>1)</sup>			8 m $\Omega$
$g_{fs}$	$V_{DS} = 10\text{ V}$ ; $I_D = 90\text{ A}$ <sup>2)</sup>	60	90	S
$C_{iss}$ $C_{oss}$ $C_{rss}$	} $V_{GS} = 0\text{ V}$ , $V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$		9400	pF
			3200	pF
			1660	pF
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	} $V_{GS} = 10\text{ V}$ , $V_{DS} = 0.5 \cdot V_{DSS}$ , $I_D = 90\text{ A}$ $R_G = 1\ \Omega$ (External)		50	ns
			90	ns
			140	ns
			65	ns
$Q_{g(on)}$ $Q_{gs}$ $Q_{gd}$	} $V_{GS} = 10\text{ V}$ , $V_{DS} = 0.5 \cdot V_{DSS}$ , $I_D = 90\text{ A}$		400	nC
			65	nC
			220	nC
$R_{thJC}$ $R_{thCK}$	with heatsink compound (0.42 K/m.K; 50 $\mu\text{m}$ )		0.30	K/W
			0.2	K/W

IXYS reserves the right to change limits, test conditions and dimensions.

$$V_{DSS} = 100\text{ V}$$

$$I_{D25} = 165\text{ A}$$

$$R_{DS(on)} = 8\text{ m}\Omega$$

$$t_{rr} \leq 250\text{ ns}$$

### Features

- Silicon chip on Direct-Copper-Bond substrate
  - High power dissipation
  - Isolated mounting surface
  - 2500V electrical isolation
- Low drain to tab capacitance (< 25pF)
- Low  $R_{DS(on)}$  HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Fast intrinsic Rectifier

### Applications

- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor control

### Advantages

- Easy assembly
- Space savings
- High power density

### Source-Drain Diode

**Characteristic Values**  
( $T_J = 25^\circ\text{C}$ , unless otherwise specified)

Symbol	Conditions	min.	typ.	max.	
$I_S$	$V_{GS} = 0\text{ V}$			180	A
$I_{SM}$	Repetitive; pulse width limited by $T_{JM}$			720	A
$V_{SD}$	$I_F = 100\text{ A}$ , $V_{GS} = 0\text{ V}$ , <sup>1)</sup>			1.5	V
$t_{rr}$	} $I_F = 50\text{ A}$ , $-di/dt = 100\text{ A}/\mu\text{s}$ , $V_R = 100\text{ V}$			250	ns
$Q_{RM}$			1.1		$\mu\text{C}$
$I_{RM}$			13		A

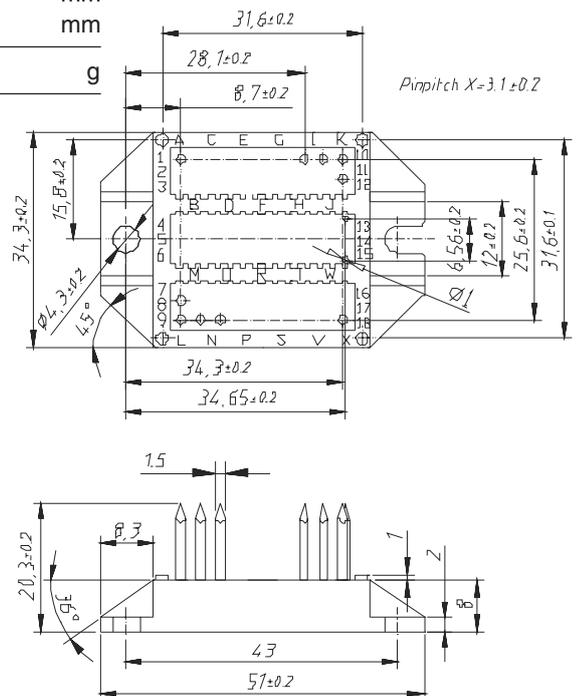
Note: <sup>1)</sup> Pulse width limited by  $T_{JM}$   
<sup>2)</sup> Pulse test,  $t \leq 300\ \mu\text{s}$ , duty cycle  $d \leq 2\%$

### Module

Symbol	Conditions	Maximum Ratings	
$T_{VJ}$		-40...+150	$^\circ\text{C}$
$T_{stg}$		-40...+125	$^\circ\text{C}$
$V_{ISOL}$	$I_{ISOL} \leq 1\text{ mA}$ ; 50/60 Hz; $t = 1\text{ s}$	3600	V~
$M_d$	mounting torque (M4)	1.5 - 2.0	Nm
		14 - 18	lb.in.
$a$	Max. allowable acceleration	50	$\text{m/s}^2$

Symbol	Conditions	Characteristic Values		
		min.	typ.	max.
$d_s$	Creepage distance on surface (Pin to heatsink)	11.2		mm
$d_A$	Strike distance in air (Pin to heatsink)	11.2		mm
<b>Weight</b>			24	g

Dimensions in mm (1 mm = 0.0394")



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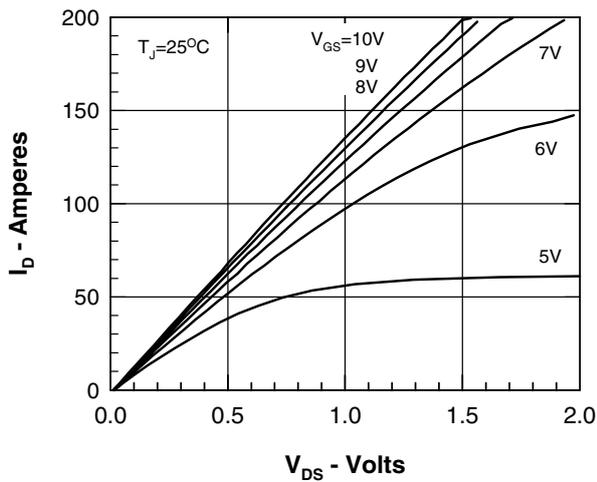


Figure 1. Output Characteristics at 25°C

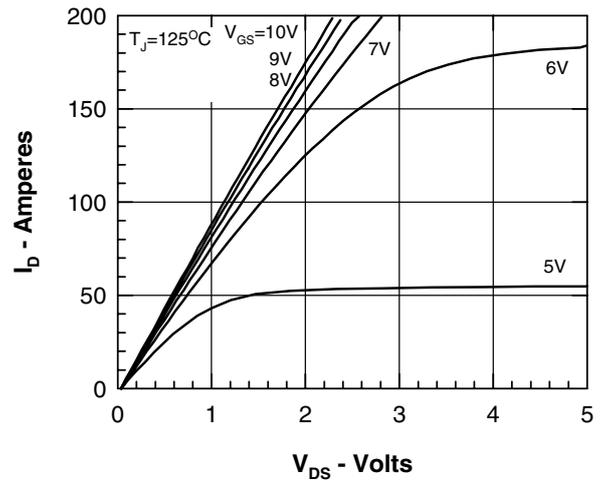


Figure 2. Output Characteristics at 125°C

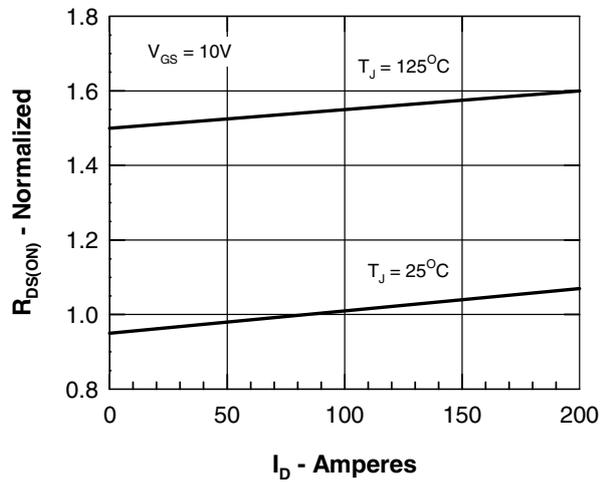


Figure 3.  $R_{DS(on)}$  normalized to 15A/25°C vs.  $I_D$

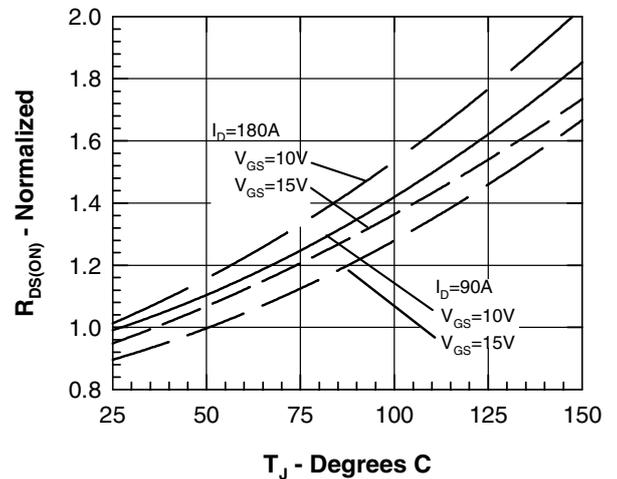


Figure 4.  $R_{DS(on)}$  normalized to 15A/25°C vs.  $T_J$

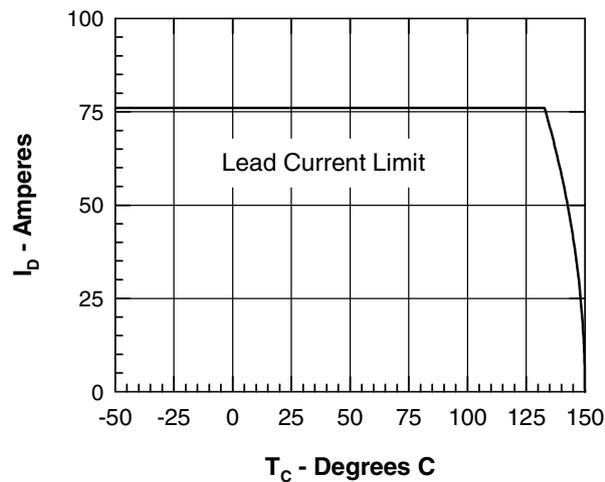


Figure 5. Drain Current vs. Case Temperature

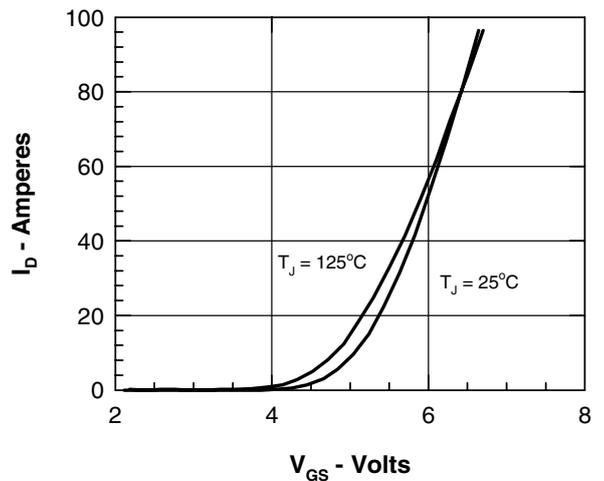


Figure 6. Admittance Curves

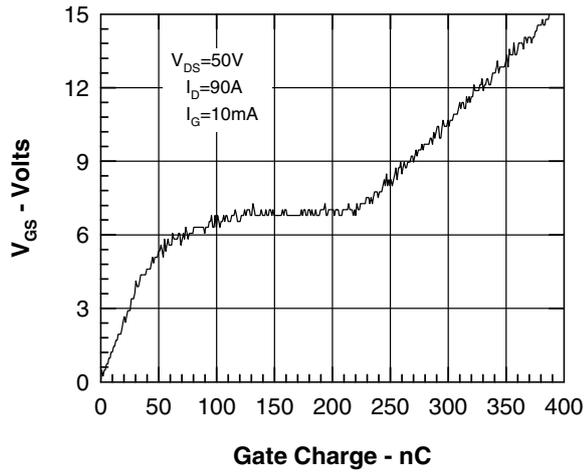


Figure 7. Gate Charge

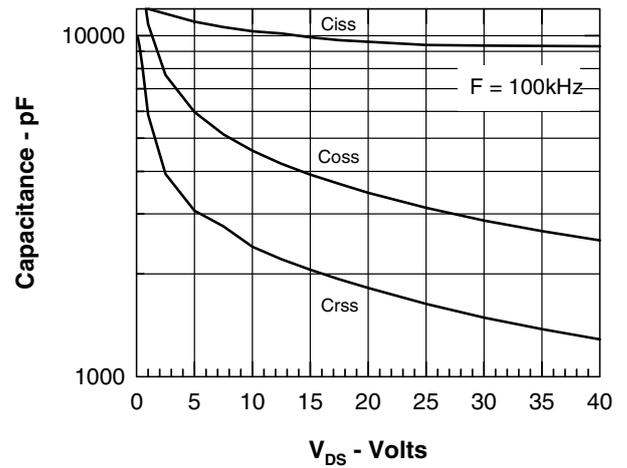


Figure 8. Capacitance Curves

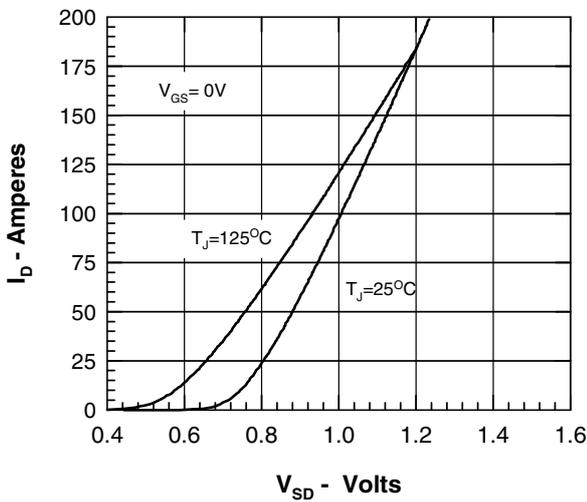


Figure 9. Forward Voltage Drop of the Intrinsic Diode

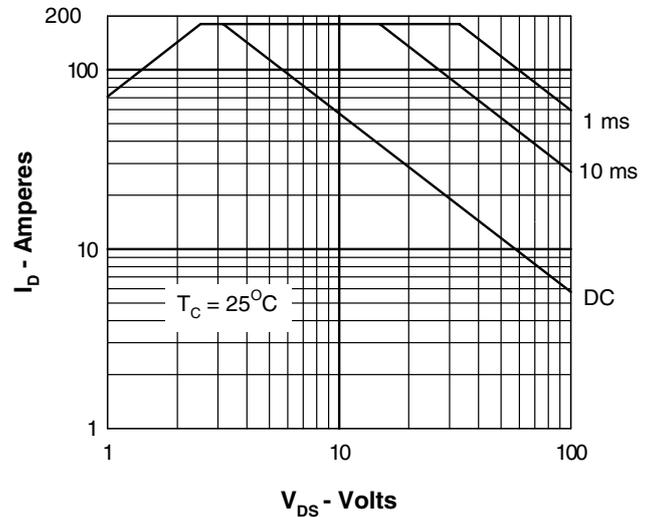


Figure 10. Forward Bias Safe Operating Area

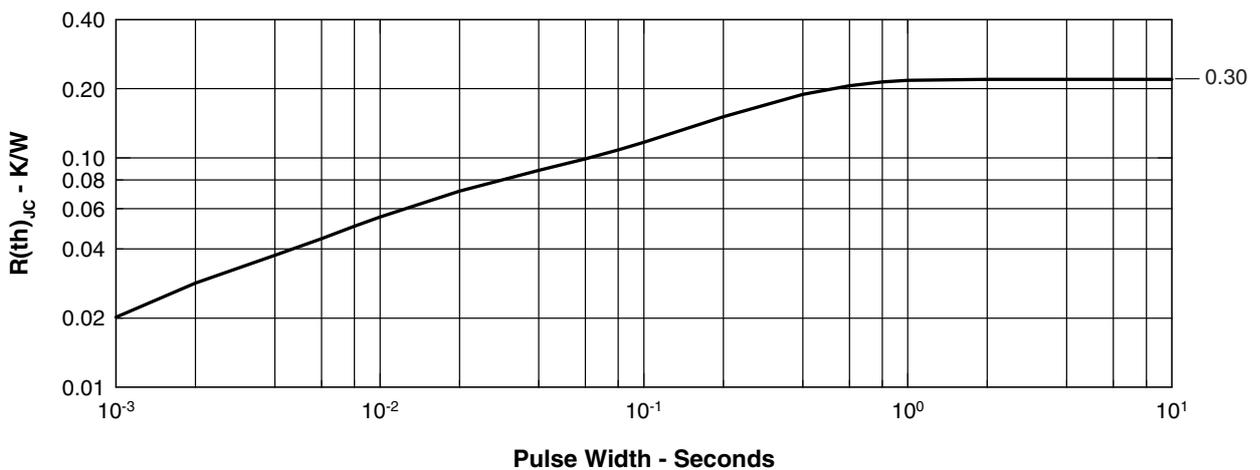


Figure 11. Typical Transient Thermal Resistance